# **NDBA100N10B**

## **Power MOSFET** 100V, 6.9mΩ, 100A, N-Channel

#### **Features**

- Low On-Resistance
- Low Gate Charge
- High Speed Switching
- 100% Avalanche Tested
- Pb-Free, Halogen Free and RoHS Compliance

#### **Specifications**

#### Absolute Maximum Ratings at Ta = 25°C

Parameter	Symbol	Value	Unit
Drain to Source Voltage	VDSS	100	V
Gate to Source Voltage	V <sub>GSS</sub>	±20	V
Drain Current (DC)	ID	100	А
Drain Current (Pulse) PW≤10μs, duty cycle≤1%	I <sub>DP</sub>	400	A
Power Dissipation Tc=25°C	PD	110	W
Junction Temperature	Tj	175	°C
Storage Temperature	Tstg	-55 to +175	°C
Source Current (Body Diode)	IS	100	А
Avalanche Energy (Single Pulse) *1	E <sub>AS</sub>	147	mJ
Lead Temperature for Soldering Purposes, 3mm from Case for 10 Seconds	TL	260	°C

#### **Thermal Resistance Ratings**

Parameter	Symbol	Value	Unit	
Junction to Case Steady State	R <sub>0JC</sub>	1.36	0000	
Junction to Ambient *2	R <sub>0JA</sub>	62.5	°C/W	

Note : \*1 VDD=48V, L=100µH, IAV=40A (Fig.1)

\*2 Surface mounted on FR4 board using recommended footprint

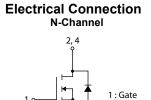
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 5 of this data sheet.



Veee	Ppo(on) Moy	
VDSS	R <sub>DS</sub> (on) Max	ID Max
100V	6.9 mΩ@15V	
	8.2 mΩ@10V	100A



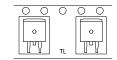








#### Packing Type : TL

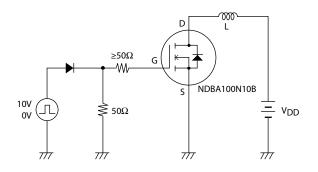


#### **Electrical Characteristics** at $Ta = 25^{\circ}C$

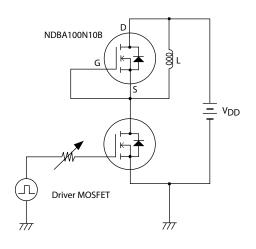
Parameter	O: make al	Quality and	Value			
	Symbol	Conditions	min	typ	max	Unit
Drain to Source Breakdown Voltage	V(BR)DSS	I <sub>D</sub> =10mA, V <sub>GS</sub> =0V	100			V
Zero-Gate Voltage Drain Current	IDSS	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V			10	μA
Gate to Source Leakage Current	IGSS	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V			±100	nA
Gate Threshold Voltage	V <sub>GS</sub> (th)	V <sub>DS</sub> =10V, I <sub>D</sub> =1mA	2		4	V
Forward Transconductance	9FS	V <sub>DS</sub> =10V, I <sub>D</sub> =50A		75		S
Static Drain to Source On-State Resistance	R <sub>DS</sub> (on)1	I <sub>D</sub> =50A, V <sub>GS</sub> =15V		5.7	6.9	mΩ
	R <sub>DS</sub> (on)2	I <sub>D</sub> =50A, V <sub>GS</sub> =10V		6.3	8.2	mΩ
Input Capacitance	Ciss			2,950		pF
Output Capacitance	Coss	V <sub>DS</sub> =50V, f=1MHz		1,250		pF
Reverse Transfer Capacitance	Crss			20		pF
Turn-ON Delay Time	t <sub>d</sub> (on)			40		ns
Rise Time	tr			385		ns
Turn-OFF Delay Time	t <sub>d</sub> (off)	See Fig.2		68		ns
Fall Time	tf			52		ns
Total Gate Charge	Qg			35		nC
Gate to Source Charge	Qgs	V <sub>DS</sub> =48V, V <sub>GS</sub> =10V, I <sub>D</sub> =100A		13		nC
Gate to Drain "Miller" Charge	Qgd			10		nC
Forward Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> =100A, V <sub>GS</sub> =0V		1.1	1.5	V
Reverse Recovery Time	trr	See Fig.3		130		ns
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>S</sub> =100A, V <sub>GS</sub> =0V, V <sub>DD</sub> =50V, di/dt=100A/μs		400		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

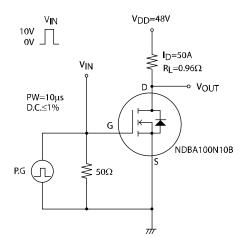
#### Fig.1 Unclamped Inductive Switching Test Circuit



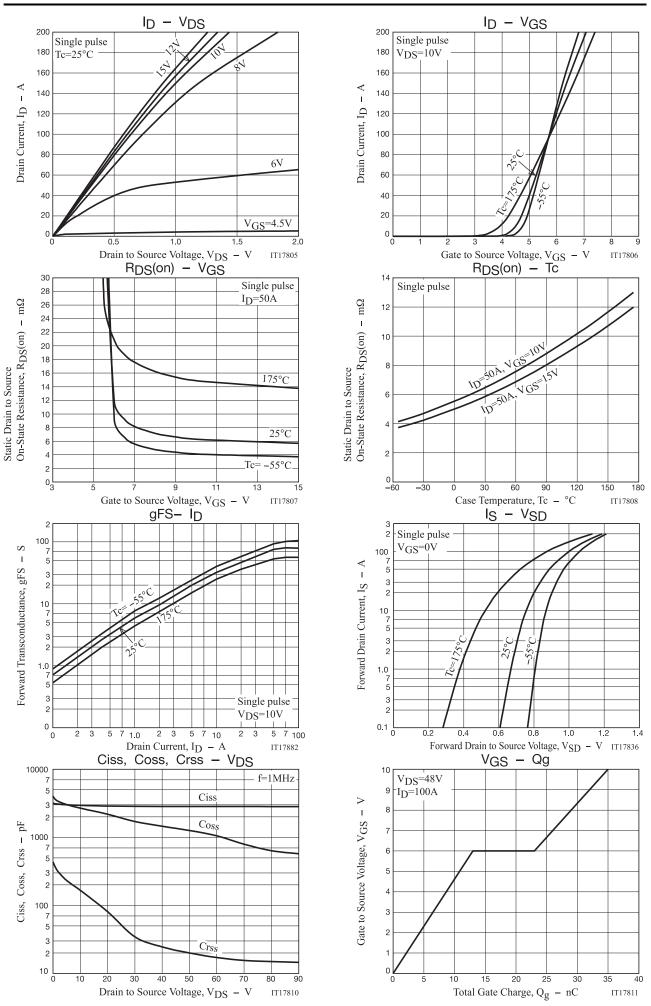
#### Fig.3 Reverse Recovery Time Test Circuit



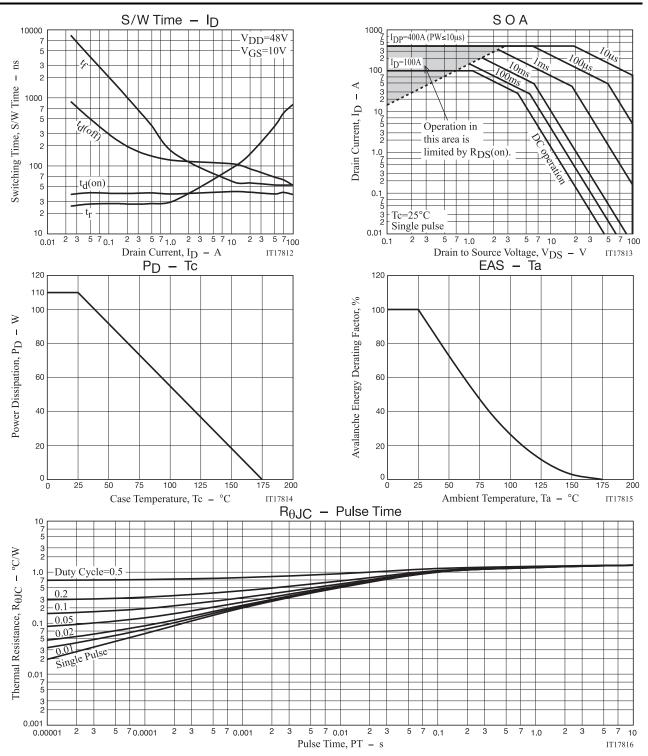
#### Fig.2 Switching Time Test Circuit



#### NDBA100N10B

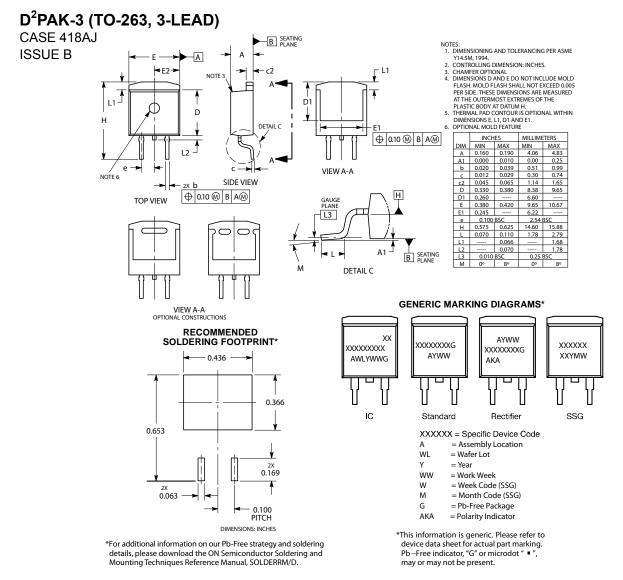


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#### **Package Dimensions**

NDBA100N10BT4H



#### **ORDERING INFORMATION**

Device	Package Shipping		note
NDBA100N10BT4H	D <sup>2</sup> PAK-3 (TO-263, 3-LEAD)	800 pcs. / Tape & Reel	Pb-Free and Halogen Free

† For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D. http://www.onsemi.com/pub\_link/Collateral/BRD8011-D.PDF

### Note on usage : Since the NDBA100N10B is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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